

### **REMARKS**

Claims 1-22 are now pending in the application. The Examiner is respectfully requested to reconsider and withdraw the rejection(s) in view of the amendments and remarks contained herein.

### **REJECTION UNDER 35 U.S.C. § 103**

Claims 1-22 stand rejected under 35 U.S.C. § 103(a) as being unpatentable over Ferrante (U.S. Pat. No. 5,847,876) in view of Yasunori (U.S. Pat. No. 6,417,619). This rejection is respectfully traversed.

Ferrante discloses the use of magnesium fluoride as a material to be deposited on a substrate. Such materials require a high temperature deposition, such as a chemical vapor deposition as disclosed in Ferrante. It is generally known by one skilled in the art that using high temperature deposition methods would generally deform, crack, or damage plastic substrates. Particularly, the high temperature cycling damages a plastic substrate where deformation and damage is undesirable. Therefore, Ferrante teaches materials and methods that are incompatible with use with a plastic substrate. In particular, as noted by the Examiner, Ferrante teaches positioning materials on a glass substrate (see Fig. 1). Therefore, one skilled in the art would not combine Ferrante, which teaches high temperature and related material, deposition methods with a plastic substrate.

In addition, even if Yasunori teaches ion beam deposition, as claimed in the presently pending claims, such deposition methods are incompatible with materials disclosed in Ferrante et al. In particular, as one skilled in the art would understand, using magnesium fluoride is incompatible with ion beam deposition methods. The materials in magnesium fluoride, particularly the fluoride which would be ionized in an ion beam deposition, becomes corrosive and does not form a selected film on a substrate. Therefore, one skilled in the art would not combine various methods, such as sputtering, ion plating, or the like, with materials disclosed in Ferrante et al. Therefore, one skilled in the art would not combine Ferrante et al. with Yasunori to achieve the presently pending claims. Even if one were to attempt to combine Yasunori and Ferrante et al., which is impractical, each of the limitations of the presently pending claims would not be taught or fairly suggested.

Even though Applicant submits that combining Ferrante et al. with Yasunori is improper, Applicant believes that prosecution and allowance of the presently pending claims may be sped by entrance of the presently submitted amendments.

Independent Claim 1 recites "ion beam depositing a lower thin layer comprising  $\text{TiO}_2$  onto a plastic substrate ... and ion beam depositing an upper thin film layer comprising at least one of  $\text{SiO}_2$  or  $\text{Al}_2\text{O}_3$  onto said lower thin film layer". As submitted by the Examiner, the art does not teach ion depositing onto a plastic substrate, a lower thin layer of titanium oxide and depositing an upper thin layer of silicon oxide and/or aluminum oxide. Therefore, the art does not teach or suggest independent Claim 1.

Independent Claim 10 recites "forming an eyeglass lens of a plastic material including a selected shape ...ion depositing an upper thin film layer including at least

one of  $\text{SiO}_2$  or  $\text{Al}_2\text{O}_3$  ... and ion depositing a lower thin film layer including  $\text{TiO}_2$  to interface the plastic eyeglass lens while maintaining the selected shape". As discussed above, the art does not teach ion depositing an upper layer of silicon oxide and/or aluminum oxide on a lower layer of titanium oxide. Further, the art does not teach ion depositing the layers on an eyeglass lens formed of a plastic material while maintaining a selected shape of the eyeglass lens.

Finally, independent Claim 15 recites "forming the selected polymer substrate into a selected shape; ion depositing a lower thin film layer to interface the selected polymer substrate ... ion depositing an upper thin film layer ... and maintaining the selected shape of the polymer substrate during the ion depositing". As the Examiner notes Ferrante et al. does not teach ion depositing material on a polymer substrate. Further, none of the references teach or suggest providing a polymer substrate including a selected shape that is maintained during the deposition of a selected material. Therefore, the references cited by the Examiner, both alone and in combination, fail to teach or suggest each of the elements of presently pending independent Claim 15.

Therefore, Applicant submits that each of the claims presently pending are neither taught nor fairly suggested by the art of reference and request that the Examiner withdraw each of the objections and allow each of the presently pending claims.

### CONCLUSION

It is believed that all of the stated grounds of rejection have been properly traversed, accommodated, or rendered moot. Applicant therefore respectfully requests that the Examiner reconsider and withdraw all presently outstanding rejections. It is believed that a full and complete response has been made to the outstanding Office Action, and as such, the present application is in condition for allowance. Thus, prompt and favorable consideration of this amendment is respectfully requested. If the Examiner believes that personal communication will expedite prosecution of this application, the Examiner is invited to telephone the undersigned at (248) 641-1600.

Respectfully submitted,

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